

ARFTG Short Course (Winter 2019)

Sunday 1/20 – Monday 1/21; 50 min presentations; 12 total time slots

Microwave Power and Traceability (Ron Ginley, NIST)

Time-domain measurements for microwave applications: What the manual doesn't tell you (Paul Hale, NIST)

Modern Network Analyzer Calibration Techniques (Rusty Myers, Keysight)

Antenna Measurements, MIMO (David Novotny, NIST)

Uncertainties in mm-wave on-wafer measurements (Uwe Arz, PTB)

Microwave Uncertainty Framework (Dylan Williams, NIST)

Machine Learning and AI (Aric Sanders, NIST)

Metrology for Over the Air Measurements (Kate Remley, NIST)

Filters and Signal Control (Dmitra Psychogiou, University of Colorado)

On-Wafer Materials Measurements (James Booth, NIST)

RF GaN Device Models and Extraction Techniques (Raj Sodhi, Keysight Technologies)

Linear and Nonlinear Vector Network Analysis (Ron Ginley, NIST)